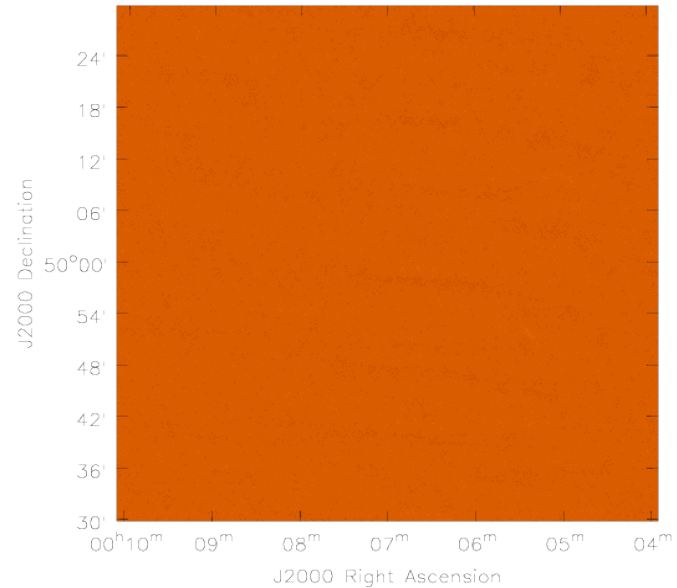
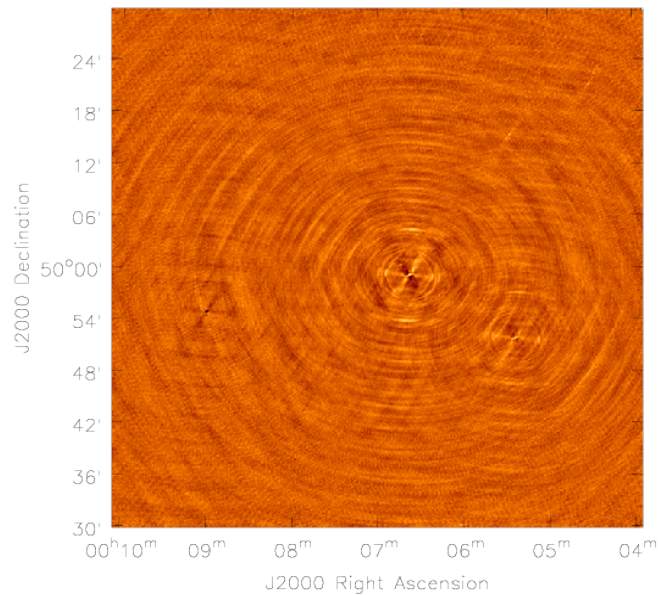


Steps towards correction of image plane effects



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Basic Interferometry

- Interferometers measure the source coherence function (the Visibility function) $V(u_{ij}, v_{ij}, w_{ij}) = \langle E_i E_j^* \rangle$

E_i is the electric field measured at antenna i

u, v, w are the projected separation between the antennas i and j

- In terms of the sky brightness distribution ($I^o(l, m)$)

$$V(u_{ij}, v_{ij}, w_{ij}) = \int \int I^o(l, m) e^{-2\pi i(u_{ij}l + v_{ij}m + w_{ij}n)} \frac{dl dm}{n}$$

- In the small angle approximation, sky is the 2D Fourier transform of the Visibility function (van Cittert-Zernike Theorem)

$$V(u_{ij}, v_{ij}) = \int \int I^o(l, m) e^{-2\pi i(u_{ij}l + v_{ij}m)} dl dm$$

$$I^o = FT[V]$$

Imaging and calibration errors

- Generic Measurement Equation:

$$V_{ij}^{Obs}(\nu, t) = G_{ij}(\nu, t) \left[\int \int X_{ij}(\nu, t) I^M(l, m) e^{2\pi i(lu_{ij} + mv_{ij})} dl dm \right]$$

↑ Data ↑ ↑ ↑ Sky
 Corruptions Sky

$G_{ij} = G_i G_j^*$ where G_i are antenna based gains (direction **independent**)

$X_{ij} = X_i(l, m) X_j(l, m)$ where X_i are image plane errors (direction **dependent**).

- $V_{ij}^{Obs} = G_{ij} \cdot [E_{ij} * V_{ij}^M]$ Unknowns are: G_{ij} , E_{ij} , and I^M .
- **SelfCal**: Given I^M and knowing E_{ij} , G_{ij} is the dominant error term.
- **Imaging/deconvolution**: Knowing G_{ij} and E_{ij} , solve for I^M

Visibility inversion

- Visibility inversion is done using the FFT algorithm which operates on a regular grid.
- V^{Obs} does not regularly sample the (u, v) plane. $V^M(u, v)$ is computed by re-sampling the grid using a Gridding Convolution Function (GCF)

$$V^M(u_{ij}, v_{ij}) = (GCF(u, v) * FFT[I^M])(u_{ij}, v_{ij})$$

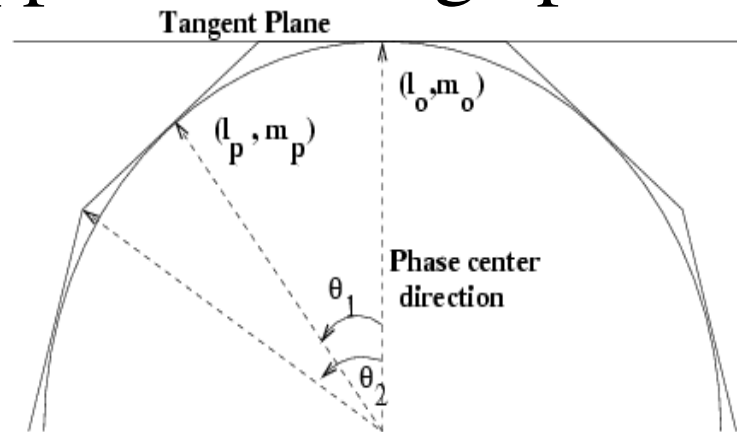
- Image plane effects can be efficiently applied by incorporating them in the GCF.
- **Challenge:** Fast evaluation of the modified GCF.

Known direction dependent errors

- Non co-planar baselines

$$V(u, v, w) = \iint I(l, m) e^{2\pi i (ul + vm + w(\sqrt{1-l^2-m^2}-1))} \frac{dl dm}{\sqrt{1-l^2-m^2}}$$

- Traditional approach: Image plane faceting



- W-projection

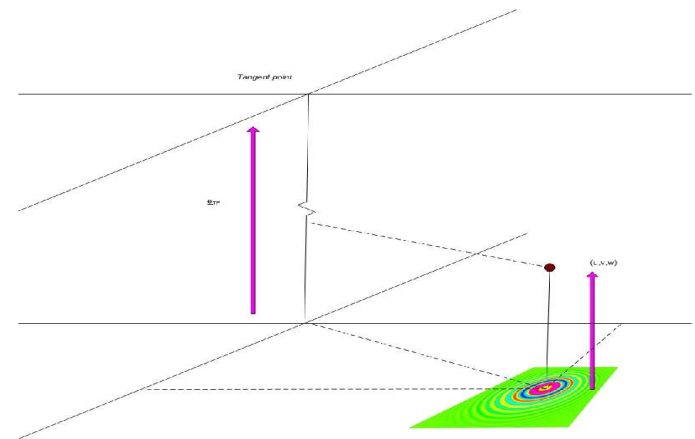
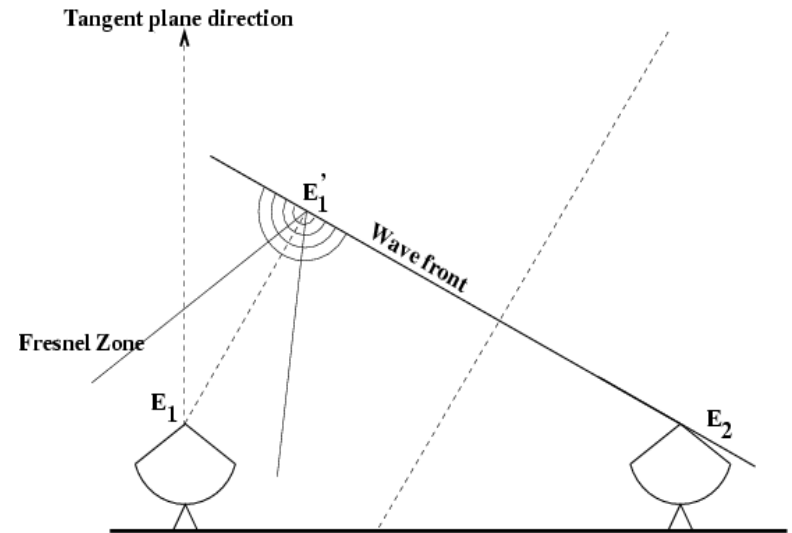
$$V_{ij}^{Obs}(u, v, w) = E_{ij} * V_{ij}^M(u, v, w=0) \quad \text{where} \quad E_{ij} = FT \left[e^{2\pi i w (\sqrt{1-l^2-m^2})} \right]$$

W-projection

- $\rho_{12} = \langle \mathbf{E}_1(u, v, w=0) \mathbf{E}_2^*(0, 0, 0) \rangle$

$\mathbf{E}_1 = \mathbf{E}'_1(u, v, w)$ propagated using Fresnel diffraction theory. The above convolution equation is reproduced with $r_F/\lambda \approx \sqrt{w}$

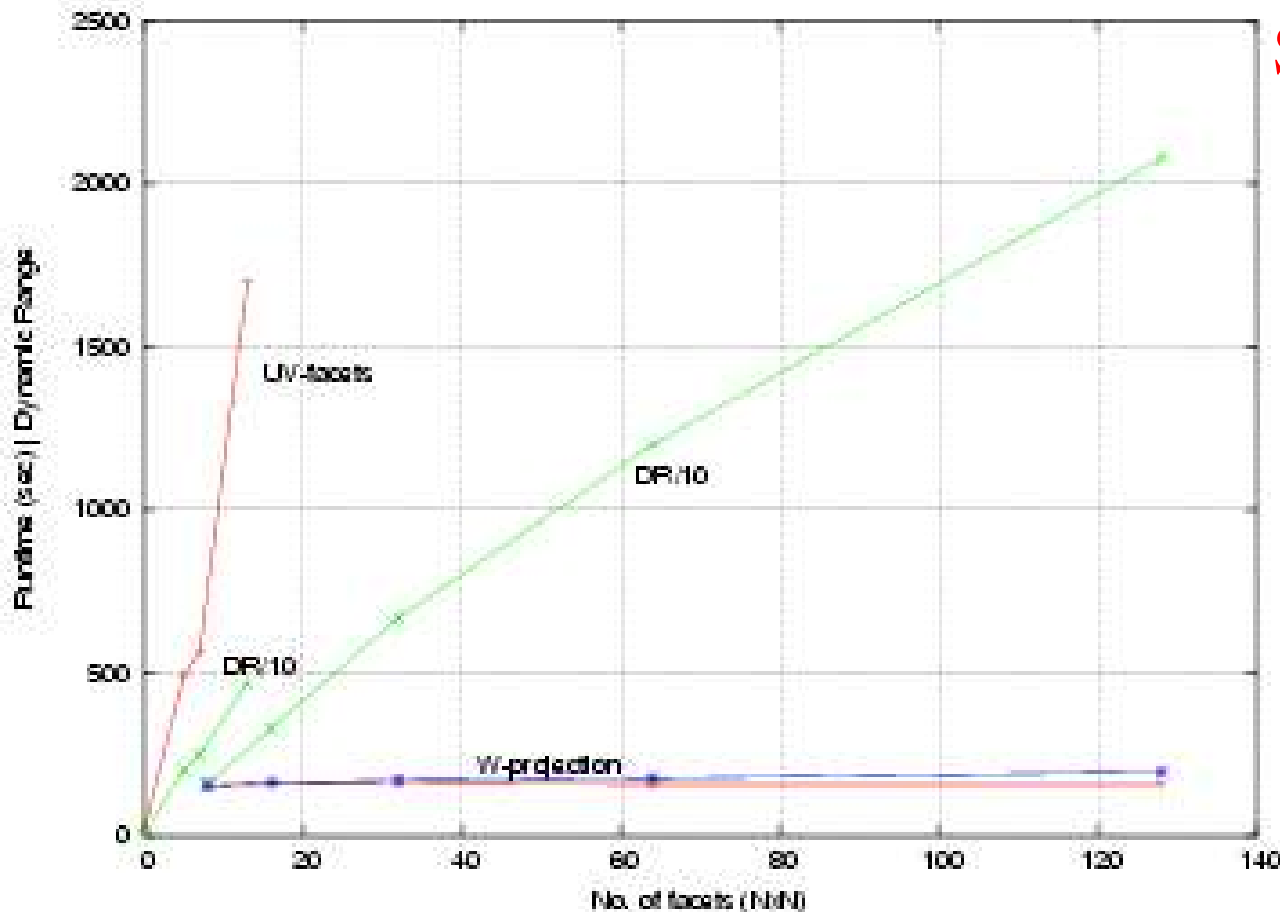
- A $w \neq 0$ interferometer is **not** a device to measure a single Fourier component.



W-projection algorithm

(CGB, EVLA Memo #67)

- Pre-compute $GCFs$ with uniform sampling in \sqrt{w} such that aliasing effects are less than the required dynamic range.



Scaling laws:

W-projection:

$$(N_{wproj}^2 + N_{GCF}^2) N_{vis}$$

UV-facet:

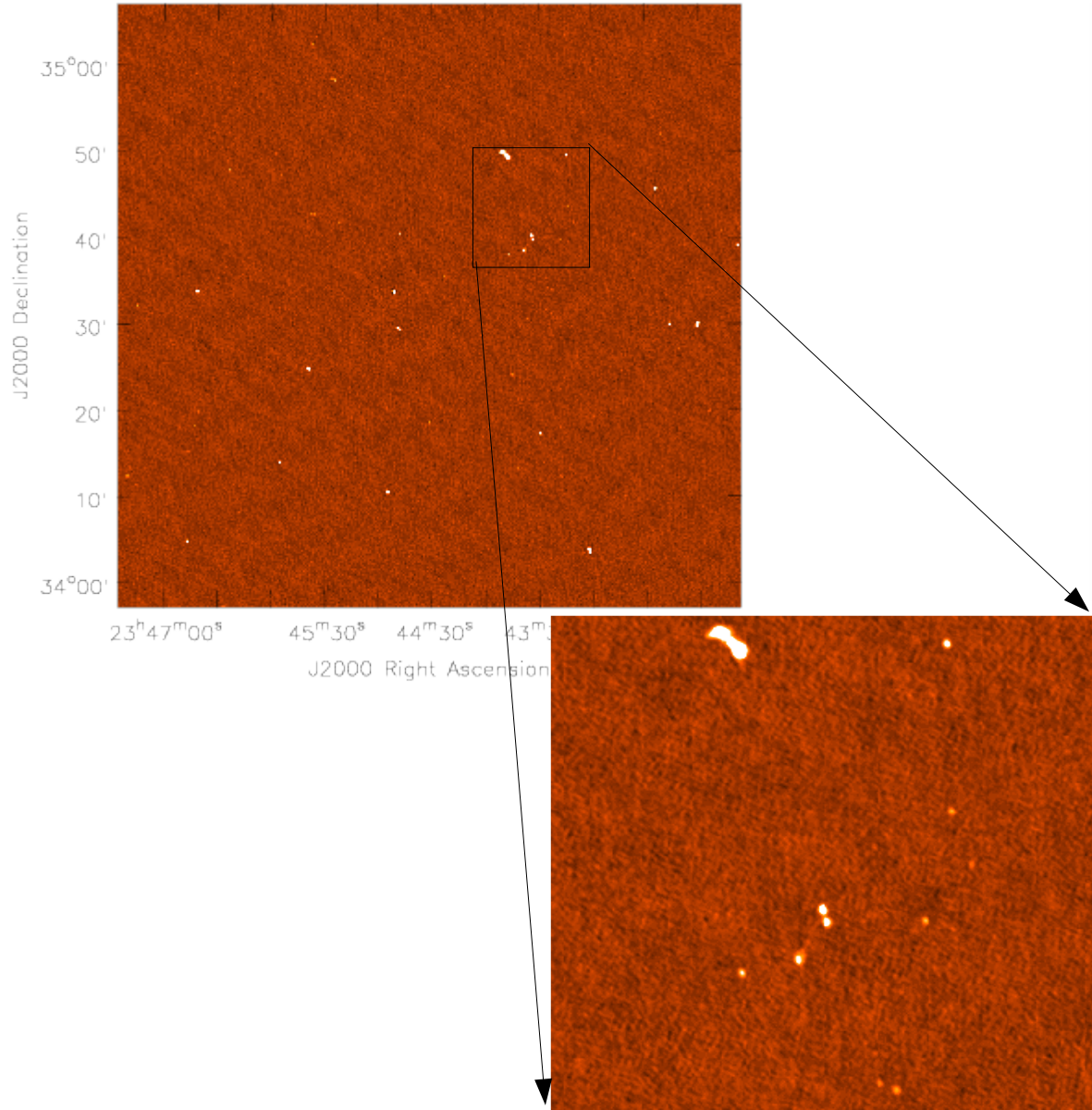
$$N_{facets}^2 N_{GCF}^2 N_{vis}$$

Ratio:

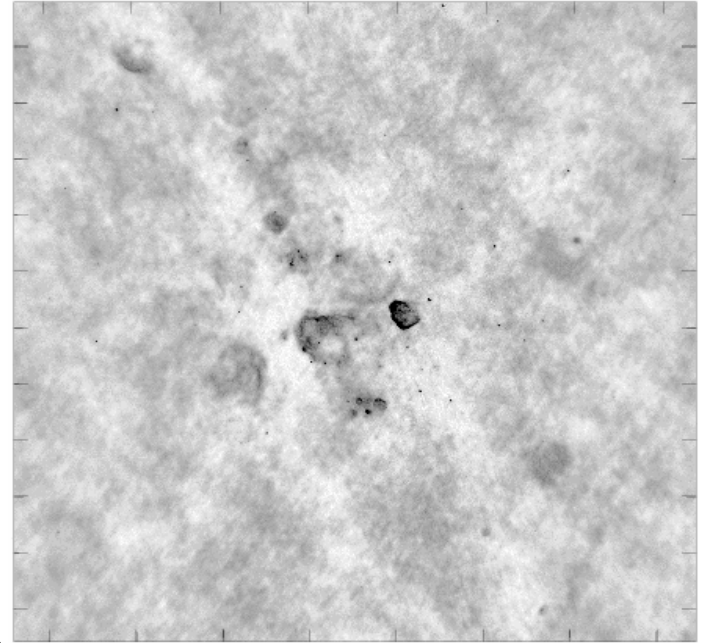
$$\approx N_{GCF}^2 \text{ for large no. of facets}$$

W-projection: Examples

GMRT P-band image of TXS2342+342 (Kanekar et al.)



Galactic Plane at P-band – VLA B,C,D (Brogan et al.)



Measured direction dependent effects

- E_{ij} as a function of direction is measured a priori

$$V_{ij}^{Obs} = G_{ij} \cdot [E_{ij} * V^M] \quad \text{where} \quad E_{ij}(l_i, l_j, u_{ij}; p_i, p_j)$$

- Primary beam effects

- Asymmetric Primary Beams:

$$E_{ij} = E_i^o * E_j^o \quad \text{where} \quad E_i^o = FT [\text{Measured } PB_i]$$

- Polarized primary beam: Beam squint

→ E_i separately measured for the two polarizations

→ Applied with the known squint

Unknown direction dependent effects

- E_{ij} as function of direction is not known a priori

$$V_{ij}^{Obs} = G_{ij} \cdot [E_{ij} * FFT[I^M]] \quad \text{where} \quad E_{ij}(l_i, l_j, u_{ij}; p_i, p_j)$$

- E_{ij} is parameterized (p_i). *Needs a solver*

- **Primary beam effects**

- Pointing offsets:

$$E_{ij} = E^0 [1 + \Delta E_{ij}(l_i, l_j; t)] \quad l_i \text{ is the pointing offset}$$

- **Ionospheric/atmospheric effects:** non-isoplanatic phases

- **Source structure** as a function of polarization and frequency: I^M is also parameterized (spectral index effects)

$$I^M = \sum_k \text{Components}(v, Poln, Position, Scale)$$

Pointing offset calibration

$$E_{ij}(l; l_i, l_j) = E_{ij}^0(l) e^{-\frac{(l_i - l_j)^2}{2}} e^{-\pi \iota u_{ij}(l_i + l_j)} \quad (l_i \text{ is the pointing offset})$$

- Visibility prediction:
 - Gridded model $V^{M, Grid} = FFT[I^M]$
 - Re-sample on measured (u, v) using E_{ij} as the GCF
for baseline $i-j$: $V_{ij}^M = E_{ij} * V^{M, Grid}$
- *GCF is different for each baseline!*
- Use lookup tables

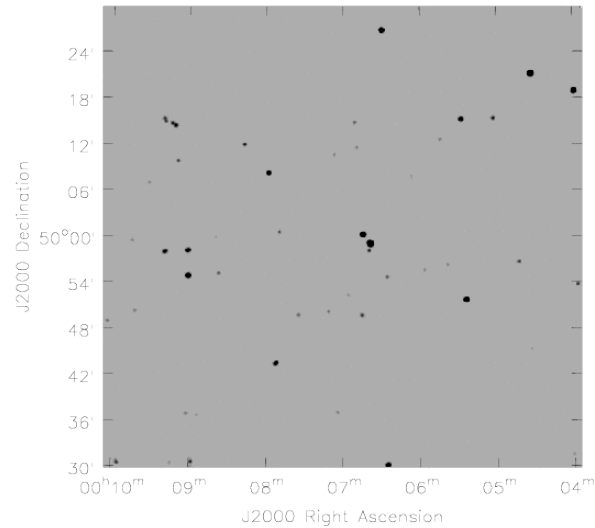
OR

- Approximation: $E_{ij} = E_{ij}^0 \left[1 - \frac{(l_i - l_j)^2}{2} \sigma^2 - \pi \iota u_{ij}(l_i + l_j) + \dots \right]$

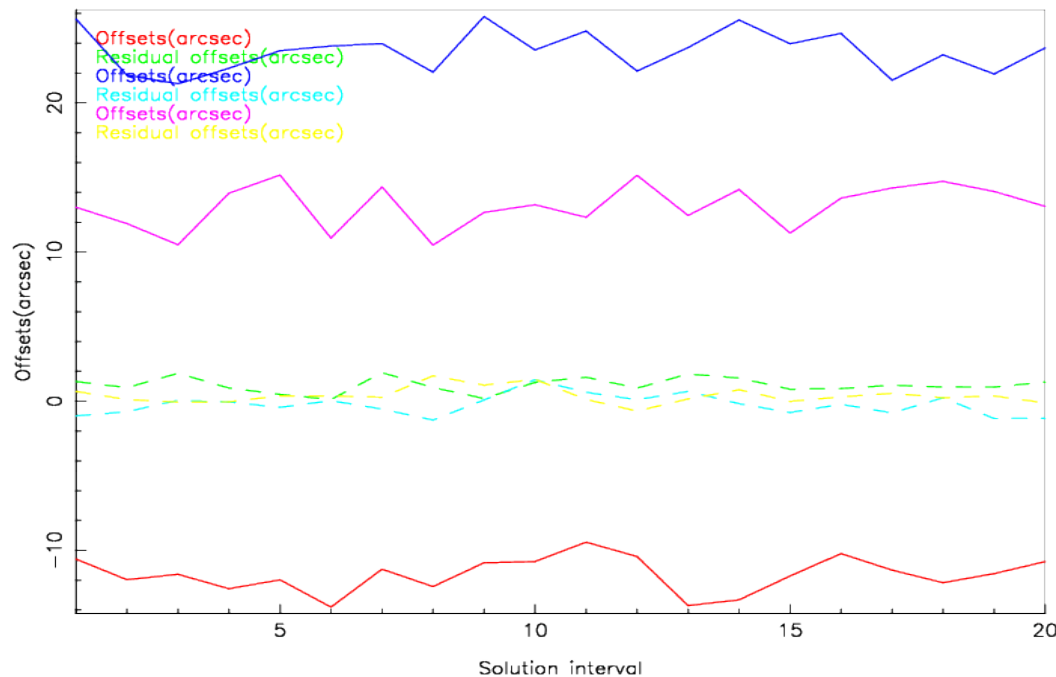
Pointing SelfCal

- Pointing errors for single pointing observation of typical L-Band field limits the RMS noise to ~ 10 microJy.
 - EVLA L-band sensitivity: 1 microJy/beam
- Mosacing dynamic range limited by pointing errors.
 - Significant fraction of ALMA observation will be mosacing observations.
- This implies significantly increased computing:
 - Each iteration involves expensive visibility prediction

Pointing SelfCal: Example



Model image using 59
sources from NVSS.
Flux range ~2-200
mJy/beam

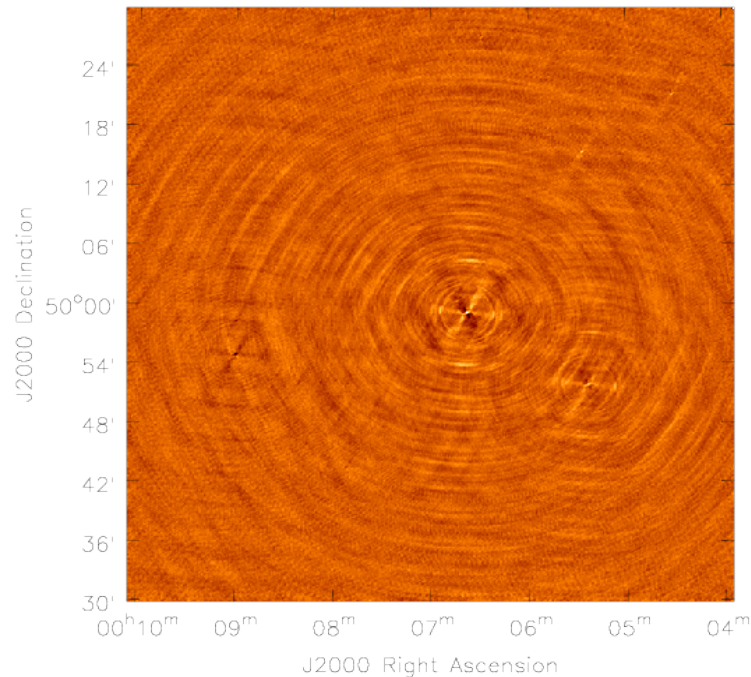


Continuous lines: Typical
antenna pointing offsets
for VLA as a function of
time (Mean between +/-
20arcsec and RMS of
5arcsec).

Dashed lines: Residual
pointing errors. RMS ~
1arcsec.

Pointing SelfCal: Example

Ref: BCG, EVLA Memo #84

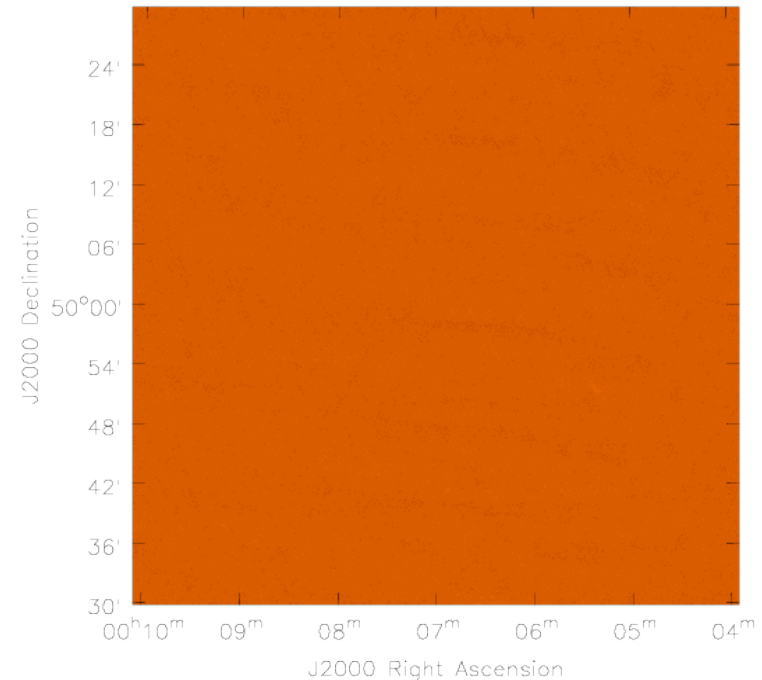


Residual image without
pointing correction:

$$\mathbf{FT}[V^{\text{Obs}} - V^{\text{M}}]$$

Peak flux ~250 microJy/beam

RMS ~ 15microJy



Residual image after pointing
correction:

$$\mathbf{FT}[V^{\text{Obs}} - E_{ij} * V^{\text{M}}]$$

Peak flux ~5microJy/beam

RMS ~ 1microJy

Wide band continuum imaging

- EVLA bandwidth ratio of 2:1

- $V(u_{ij}, v_{ij}) = \sum_{\nu_k} V(u_{ij}, v_{ij}; \nu_k) = \sum_{\nu_k} P_{ij}(\nu_k) FT[I^D(\nu_k)]$

Sky emission, the Primary Beams, etc. become a function of frequency.

Ideas: Apply PB effects during predict. Sky model parameterized in frequency as well.

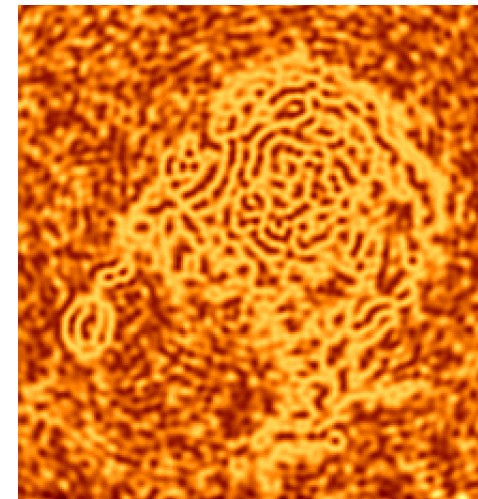
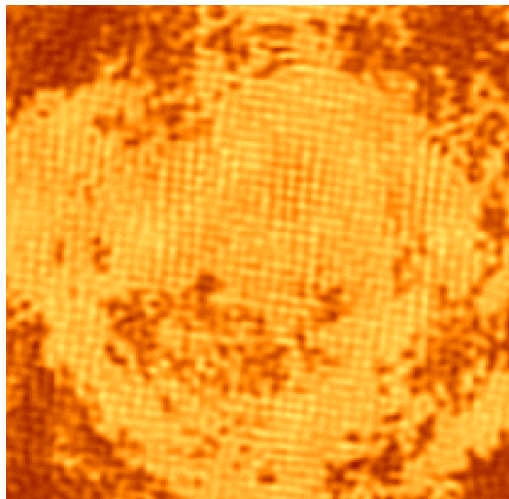
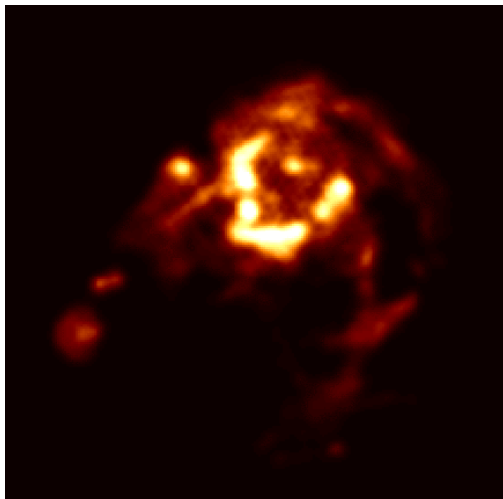
- Combining Scale sensitive + frequency sensitive deconvolution with image plane corrections.
- Work in progress: Extension of MSF and Scale-sensitive Clean (Bhatnagar&Cornwell, A&A, 2004, in press)

Scale sensitive deconvolution-I

- Pixel-to-pixel noise in the image is correlated at the scale of the resolution element

$$I^D = B * I^o + B * I^N \quad \text{where } I^N = FT [\text{Visibility Noise}]; B = PSF$$

- The scale of emission *fundamentally* separates signal (I^o) from the noise (I^N).
- Multi-Scale Clean (Cornwell & Holdaway, 2004, in prep)
 - Decompose the sky in a set of components at few scales $I^M = \sum_{k=1}^N A_k P(\text{Scale}_k)$

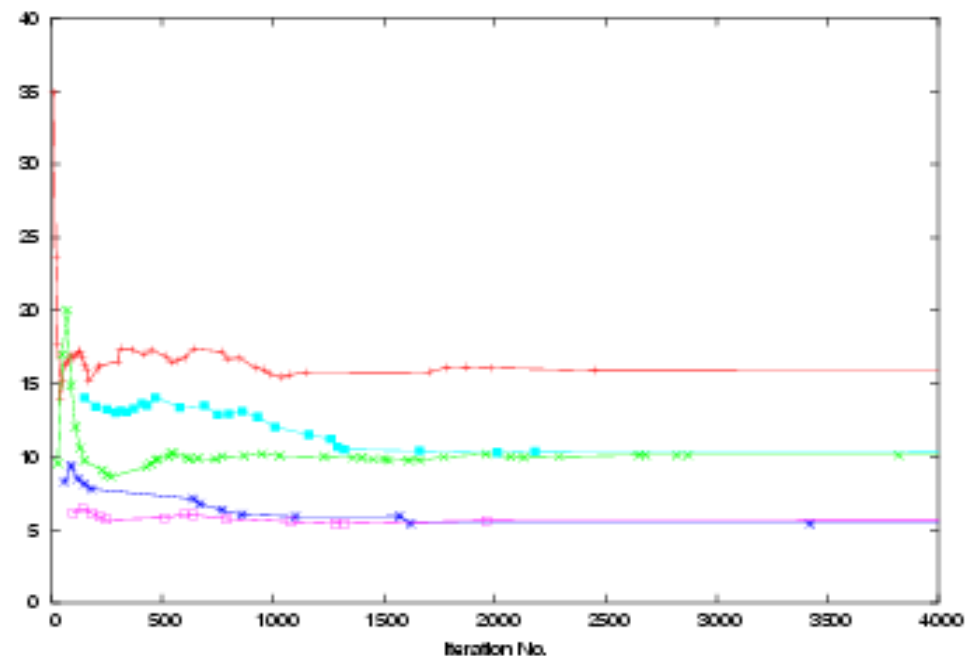
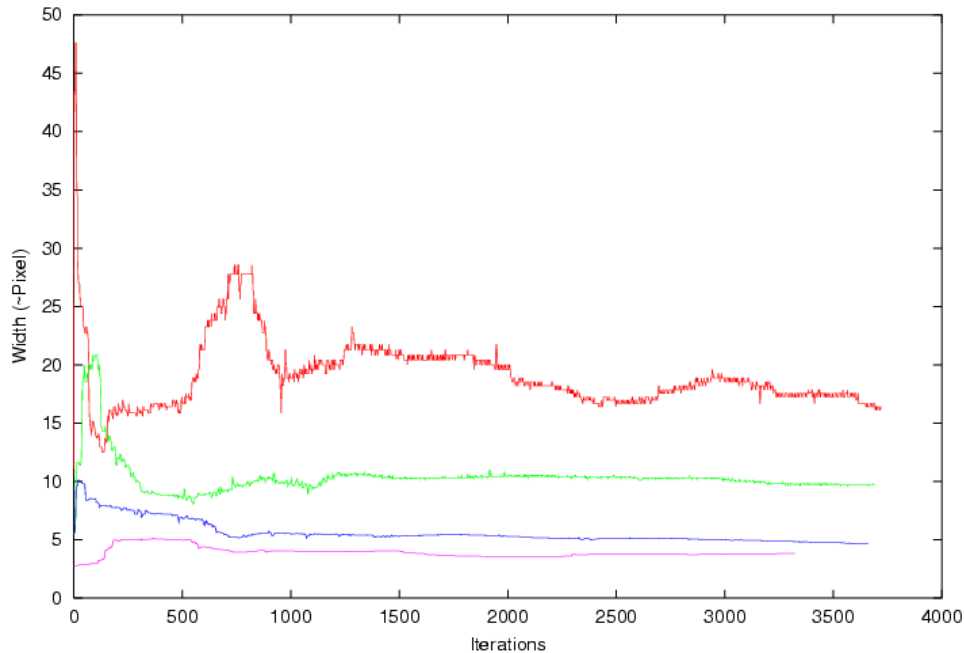
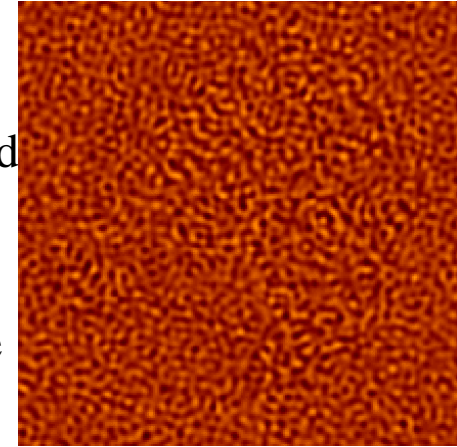


Scale sensitive deconvolution-II

- Asp-Clean (Bhatnagar & Cornwell, A&A, in press)
 - Explicitly solve for the local scale, position and amplitude of the pixel model

$$I^M = \sum_k A_k P(\text{Scale}_k, \text{Pos}_k)$$

- Large scale emission and asymmetric structures are better reconstructed
- Computationally expensive: cost increases with the no. of components
- Acceleration: Solve in a sub-space; adaptively determine the sub-space



Ionospheric phase correction

- $V_{ij}^{Obs}(\nu, t) = \int \int K_{ij}(l, m; \nu, t) I^M(l, m) e^{2\pi i(u_{ij}l + v_{ij}m)} dl dm$

where K_{ij} is the ionospheric, direction dependent phase

- The general form for residuals: $V_{ij}^R = V_{ij}^{Obs} - X_{ij} * FT[I^M]$

where $X_{ij} = W_{ij} \cdot E_{ij} \cdot K_{ij}$ (and other direction dependent terms)

- Express ionospheric phase in the antenna beam using ionospheric physics/geometrical effects/primary beam effects (de-focusing, time varying illumination, etc.)

- X_{ij} is separable into antenna based quantities $X(p_i) \cdot X^*(p_j)$
Solve for p_i 's

Computing and I/O costs

- Increase in computing due to more sophisticated parameterization
 - Deconvolution: Fast evaluation of $B * \sum_k A_k P(\text{Scale}_k, \text{Pos}_k)$
 - Calibration: Fast evaluation of $E_{ij} * V^M$
- Cost of computing residual visibilities is dominated by I/O costs for large datasets (~200GB for EVLA)
 - Deconvolution: Approx. 20 access of the entire dataset
 - Calibration: Each trial step in the search accesses the entire dataset
- Solutions: Analytical approximations, caching, Parallel computing and I/O,...